

N-Channel Enhancement Mode MOSFET

Feature

40V/340A

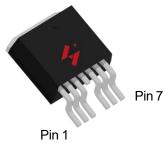
R_{DS(ON)}= 1.2 m Ω (typ.) @VGS = 10V R_{DS(ON)}= 1.4 m Ω (typ.) @VGS = 4.5V

- 100% Avalanche Tested
- 100% DVDS
- Reliable and Rugged
- Halogen Free and Green Devices Available (RoHS Compliant)

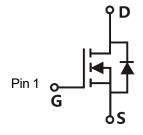
Applications

- Switching application
- Li-battery protection

Pin Description



TO-263-6L



Pin 2,3,5,6,7

Single N-Channel MOSFET

Ordering and Marking Information



Package Code

B6: TO-263-6L

Date Code XYMXXXXXX

Note: HUAYI halogen free products contain molding compounds/die attach materials and 100% matte tin plate Termi-Nation finish; which are fully compliant with RoHS. HUAYI halogen free products meet or exceed the halogen free require-ments of IPC/JEDEC J-STD-020 for MSL classification at halogen free peak reflow temperature. HUAYI defines "Green" to mean halogen free (RoHS compliant) and halogen free (Br or CI does not exceed 900ppm by weight in homogeneous material and total of Br and CI does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit			
Common Ratings (Tc=25°C Unless Otherwise Noted)						
VDSS	Drain-Source Voltage		40	V		
Vgss	Gate-Source Voltage		±20	V		
TJ	Junction Temperature Range		55 (475	°C		
Тѕтс	Storage Temperature Range		-55 to 175	°C		
ls	Source Current-Continuous(Body Diode) Tc=25°C		340	А		
Mounted on	Mounted on Large Heat Sink					
lрм	Pulsed Drain Current *	Tc=25°C	1200	А		
	O to the second	Tc=25°C	340	Α		
ID	ID Continuous Drain Current	Tc=100°C	240	А		
	M : B 5: : ::	Tc=25°C	333	W		
Po	Maximum Power Dissipation	Tc=100°C	166	W		
R_{θ} JC	Thermal Resistance, Junction-to-Case		0.45	°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient **		62.5	°C/W		
Eas	Single Pulsed-Avalanche Energy *** L=0.3mH		1470	mJ		

Note: * Repetitive rating; pulse width limited by max.junction temperature.

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

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Symbol	Parameter	Test Conditions	Min	Тур.	Max	Unit	
Static Cha	Static Characteristics						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =250μA	40	-	-	V	
1	Duning to Common London Commont	V _{DS} =40V,V _{GS} =0V	-	-	1	μA	
IDSS	Drain-to-Source Leakage Current	TJ=125°C	-	-	50	μA	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250µA	1.0	2.0	3.0	V	
Igss	Gate-Source Leakage Current	V _G S=±20V,V _D S=0V	-	-	±100	nA	
Decree	Drain Source On State Registance	V _{GS} =10V,I _{DS} =40A	-	1.2	1.6	mΩ	
Rds(on)	Drain-Source On-State Resistance V _{GS} =4.5V,I _{DS} =40A		-	1.4	1.8	mΩ	
Diode Cha	Diode Characteristics						
VsD	Diode Forward Voltage	IsD=40A,VGS=0V	-	0.8	1.0	V	
trr	Reverse Recovery Time	la==404 dla=/dt=4004/ua	-	36	-	ns	
Qrr	Reverse Recovery Charge	IsD=40A,dIsD/dt=100A/µs	-	40	-	nC	

^{**} Surface mounted on 1in2 FR-4 board.

^{***} Limited by T_Jmax , starting T_J=25°C, L = 0.3mH, R_G= 25Ω , V_GS =10V.



Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Ols al	Boundary	Toot Conditions	HYG013N04LR1			l los id
Symbol	Parameter	Test Conditions	Min	Тур.	Max	Unit
Dynamic Characteristics						
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=500KHz	-	0.8	-	Ω
Ciss	Input Capacitance	V _G S=0V,	-	14240	-	
Coss	Output Capacitance	V _{DS} =25V,	-	1238	-	pF
Crss	Reverse Transfer Capacitance	Frequency=500KHz	-	1028	-	
td(ON)	Turn-on Delay Time		-	37	-	
Tr	Turn-on Rise Time	$V_{DD}=20V,R_{G}=4\Omega,$	-	104	-	
td(OFF)	Turn-off Delay Time	IDS=40A,VGS=10V	-	200	-	ns
Tf	Turn-off Fall Time		-	134	-	
Gate Cha	Gate Charge Characteristics					
Qg	Total Gate Charge(V _{GS} =10V)		-	292	-	
Qg	Total Gate Charge(V _{GS} =4.5V)		-	147	-	
Qgs	Gate-Source Charge	V _{DS} =32V, I _{Ds} =40A	-	50	-	nC
Qgd	Gate-Drain Charge		-	75	-	
V _{plateau}	Gate plateau voltage		-	3.5	-	٧

Note: *Pulse test, pulse width ≤ 300us, duty cycle ≤ 2%



Typical Operating Characteristics

Figure 1: Power Dissipation

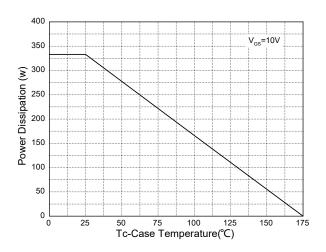


Figure 3: Safe Operation Area

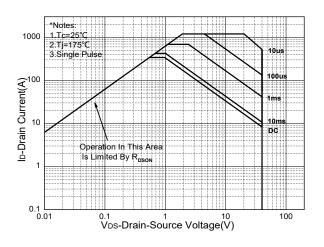


Figure 5: Output Characteristics

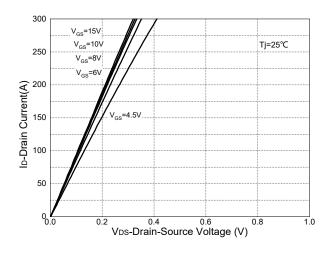


Figure 2: Drain Current

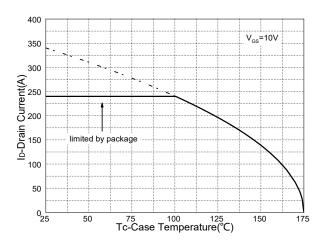


Figure 4: Thermal Transient Impedance

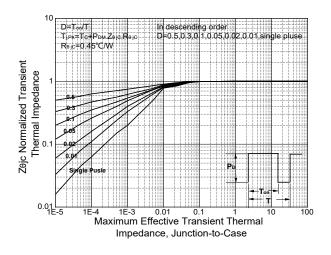
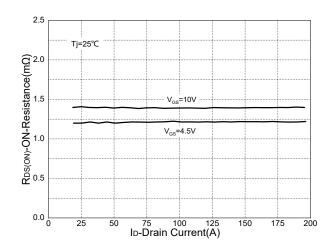


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

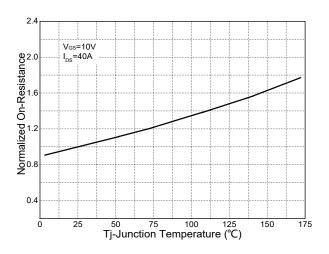


Figure 8: Source-Drain Diode Forward

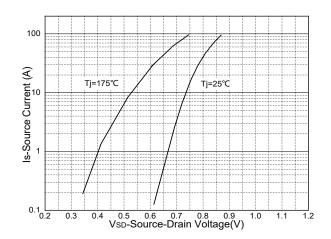


Figure 9: Capacitance Characteristics

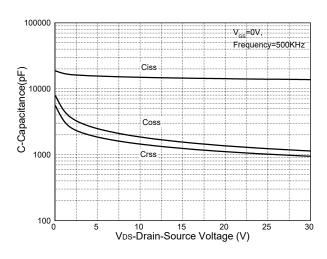
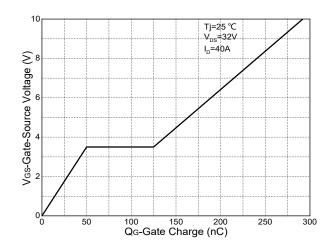
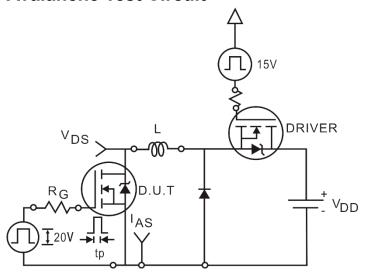


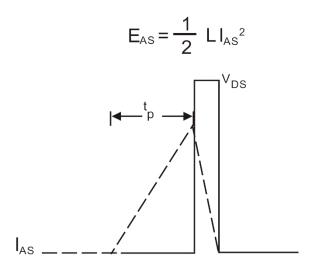
Figure 10: Gate Charge Characteristics



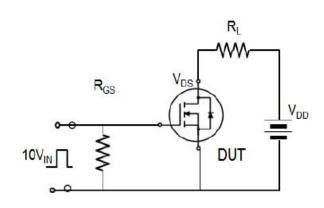


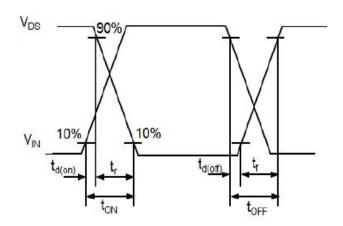
Avalanche Test Circuit



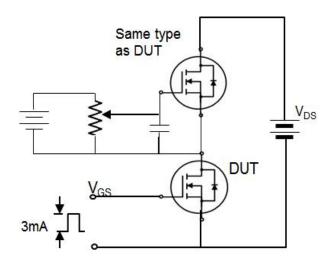


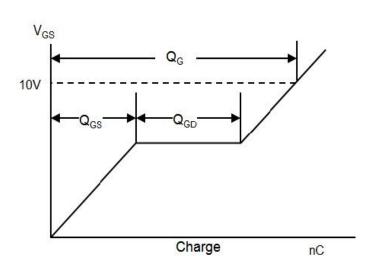
Switching Time Test Circuit





Gate Charge Test Circuit





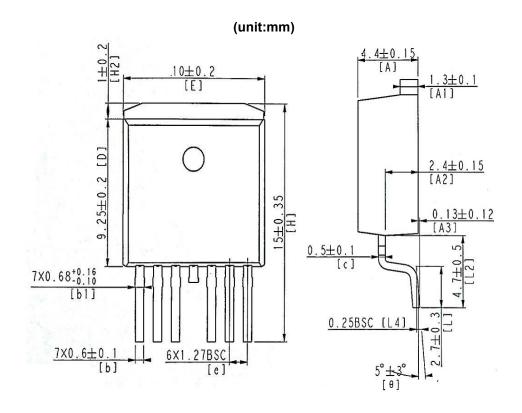


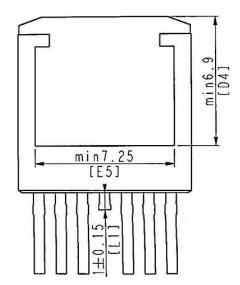
Device Per Unit

Package Type	Unit	Quantity
TO-263-6L	Reel	800

Package Information

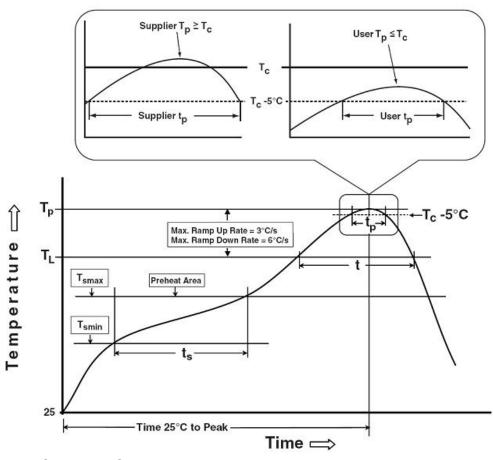
TO-263-6L







Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly			
Preheat & Soak					
Temperature min (T _{smin})	100 °C	150 °C			
Temperature max (T _{smax})	150 °C	200 °C			
Time (Tsmin to Tsmax) (t _s)	60-120 seconds	60-120 seconds			
Average ramp-up rate (T _{smax} to T _P)	3 °C/second max.	3°C/second max.			
Liquidous temperature (T₋)	183 °C	217 °C			
Time at liquidous (t∟)	60-150 seconds	60-150 seconds			
Peak package body Temperature (T _P)*	See Classification Temp in table 1	SeeClassification Tempin table 2			
Time (t _P)** within 5°C of the specified classification temperature (T _c)	20** seconds	30** seconds			
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.			
Time 25°C to peak temperature	6 minutes max.	8 minutes max.			

^{*}Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

HYG013N04LR1B6



Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description	
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C	
HTRB	JESD-22, A108	168/500 Hrs, Bias @ 150°C	
HTGB	JESD-22, A108	168 /500 Hrs, V _{gs} 100% @ 150°C	
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C	
TCT	JESD-22, A104	250/500 Cycles, -55°C~150°C	

Customer Service

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